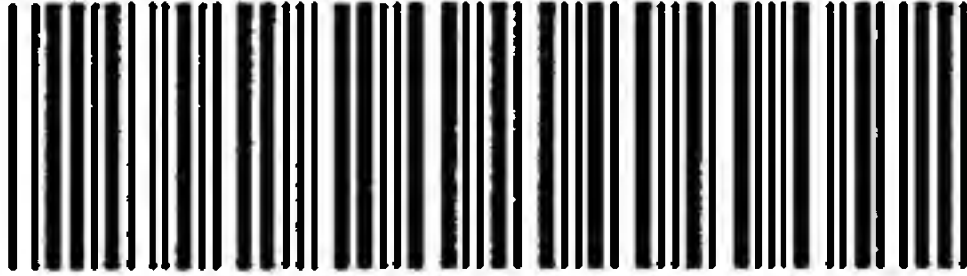


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/065,552	SAWADA ET AL.	
	Examiner	Art Unit	
	Wai-Sing Louie	2814	

SEARCHED			
Class	Subclass	Date	Examiner
438	14-18	11/15/2004	WSL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
438/14,16,18		11/22/2005	WSL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
wafer charge measurement, liquid electrode, capacitance/voltage, C/V technique, carrier density, gallium	11/15/2004	WSL